

# FDD6676S

# 30V N-Channel PowerTrench® MOSFET

### **General Description**

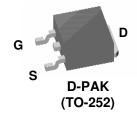
The FDS6676S is designed to replace a DPAK MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low  $R_{\text{DS}(\text{ON})}$  and low gate charge. The FDD6676S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

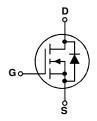
### **Applications**

DC/DC converter

### **Features**

- 78 A, 30 V  $R_{DS(ON)} = 6.0 \ m\Omega \ @V_{GS} = 10 \ V$   $R_{DS(ON)} = 7.1 \ m\Omega \ @V_{GS} = 4.5 \ V$
- Low gate charge
- · Fast Switching
- High performance trench technology for extremely low  $R_{\mbox{\scriptsize DS(ON)}}$





Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	V
V <sub>GSS</sub>	Gate-Source Voltage		±16	V
I <sub>D</sub>	Drain Current - Continuous	(Note 3)	78	Α
	- Pulsed	(Note 1a)	100	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1)	70	W
		(Note 1a)	3.1	
		(Note 1b)	1.3	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperat	ture Range	−55 to +150	°C

### **Thermal Characteristics**

R <sub>0JC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
R <sub>eJA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
FDD6676S	FDD6676S	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Not	e 2)	I	I		
W <sub>DSS</sub>	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 15 \text{ V}$ , $I_D = 16 \text{A}$			250	mJ
I <sub>AR</sub>	Drain-Source Avalanche Current				16	Α
Off Char	acteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA	30			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, Referenced to 25°C		24		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			500	μΑ
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 16 \text{ V},  V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	1	1.3	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, Referenced to 25°C		-0.9		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$\begin{aligned} &V_{GS} = 10 \text{ V}, & I_D = 16 \text{ A} \\ &V_{GS} = 4.5 \text{ V}, & I_D = 15 \text{ A} \\ &V_{GS} = 10 \text{ V}, & I_D = 16 \text{ A}, T_J = 125^{\circ}\text{C} \end{aligned}$		4.6 5.2 7.2	6.0 7.1 9.0	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 16 \text{ A}$		79		S
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$	60			Α
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance			4770		pF
Coss	Output Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		840		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1.0 MHz		305		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 0 V, f = 1.0 MHz		1.5		Ω
Switchir	ng Characteristics (Note 2)		1			
t <sub>d(on)</sub>	Turn-On Delay Time			13	23	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		13	23	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		86	138	ns
t <sub>f</sub>	Turn-Off Fall Time			34	54	ns
Qg	Total Gate Charge			41	58	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{DS} = 15V,$ $I_{D} = 16 A,$ $V_{GS} = 5 V$		10		nC
Q <sub>qd</sub>	Gate-Drain Charge	1 VGS - 0 V		10		nC

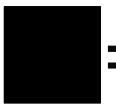
### **Electrical Characteristics** (continued)

T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Se	Drain-Source Diode Characteristics and Maximum Ratings					
Is	Maximum Continuous Drain-Source Diode Forward Current				3.5	Α
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_{S} = 3.5 \text{ A}$ (Note 2)		385	700	mV
t <sub>RR</sub>	Diode Reverse Recovery Time			29		ns
I <sub>RM</sub>	Maximum Recovery Current	$dI_F/dt = 300A/us, I_F = 16A$		2.1		Α
Q <sub>RR</sub>	Diode Reverse Recovery Charge			30		nC

#### Notes

 R<sub>BJA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>BJC</sub> is guaranteed by design while R<sub>BCA</sub> is determined by the user's board design.



a)  $R_{\theta,JA} = 40$  °C/W when mounted on a  $1 \text{in}^2$  pad of 2 oz copper



b)  $R_{\theta JA} = 96^{\circ}C/W$  when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

3. Maximum current is calculated as:  $\sqrt{\frac{P_D}{R_{DS(ON)}}}$ 

where  $P_D$  is maximum power dissipation at  $T_C$  = 25°C and  $R_{DS(on)}$  is at  $T_{J(max)}$  and  $V_{GS}$  = 10V. Package current limitation is 21A

## **Typical Characteristics**

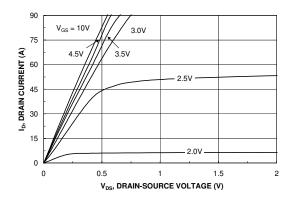


Figure 1. On-Region Characteristics

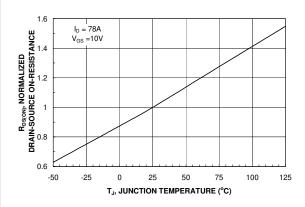


Figure 3. On-Resistance Variation with Temperature

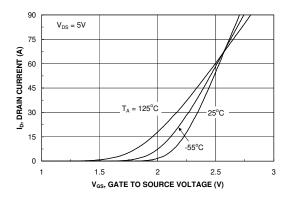


Figure 5. Transfer Characteristics

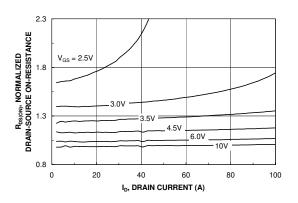


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

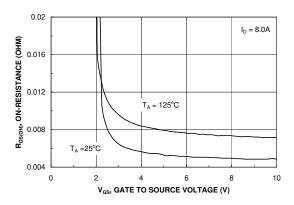


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

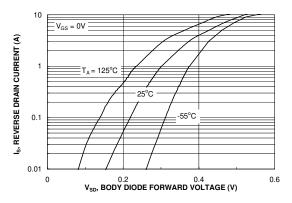
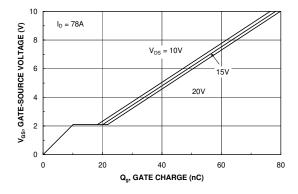


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

## **Typical Characteristics**



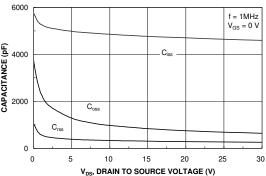


Figure 7. Gate Charge Characteristics

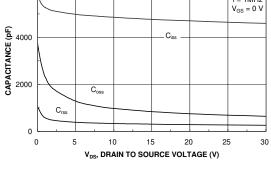
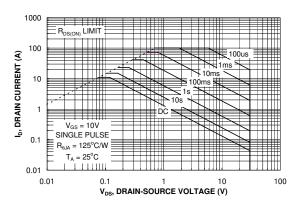


Figure 8. Capacitance Characteristics



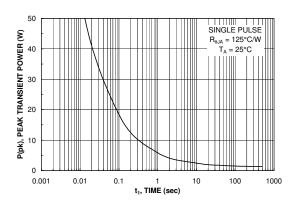


Figure 9. Maximum Safe Operating Area

Figure 10. Single Pulse Maximum **Power Dissipation** 

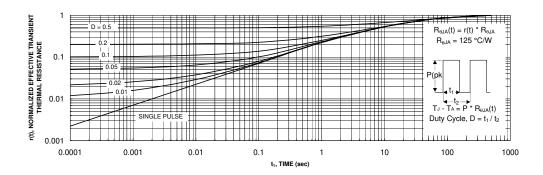


Figure 11. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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